

Radiation Hardened, High Speed, Low Power Output Limiting, Closed-Loop-Buffer Amplifier

August 1996

Features

- Electrically Screened to SMD 5962F9678501VPA
- MIL-PRF-38535 Class V Compliant
- User Programmable Output Voltage Limiting
- User Programmable For Closed-Loop Gains of +1, -1 or +2 Without Use of External Resistors
- Standard Operational Amplifier Pinout
- Fast Overdrive Recovery <1ns (Typ)
- Low Supply Current..... 6.9mA (Typ)
- Excellent Gain Accuracy..... 0.99V/V (Typ)
- Wide -3dB Bandwidth 225MHz (Typ)
- Fast Slew Rate 1135V/ μ s (Typ)
- High Input Impedance 1M Ω (Typ)
- Excellent Gain Flatness (to 50MHz) ± 0.1 dB (Typ)
- Total Gamma Dose 300K RAD (Si)
- Neutron Damage TBD (When Tests Complete)
- Latch Up None (DI Technology)

Applications

- Flash A/D Driver
- Video Switching and Routing
- Pulse and Video Amplifiers
- Wideband Amplifiers
- RF/IF Signal Processing
- Imaging Systems

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
5962F9678501VPA	-55 to 125	8 Ld Cerdip	GDIP1-T8
HFA1115IP (Sample)	-40 to 85	8 Ld PDIP	E8.3
HFA11XXEVAL	Evaluation Board		

Description

The HS-1115RH is a radiation hardened, high speed closed loop buffer featuring both user programmable gain and output limiting. They are QML approved and processed in full compliance with MIL-PRF-38535. Manufactured in proprietary, complementary bipolar UHF-1 (DI bonded wafer) process, the HS-1115RH also offers a wide -3dB bandwidth of 225MHz, very fast slew rate, excellent gain flatness and high output current.

This buffer is the ideal choice for high frequency applications requiring output limiting, especially those needing ultra fast overload recovery times. The limiting function allows the designer to set the maximum positive and negative output levels, thereby protecting later stages from damage or input saturation. The HS-1115RH also allows for voltage gains of +2, +1, and -1, without the use of external resistors. Gain selection is accomplished via connections to the inputs, as described in the "Application Information" text. The result is a more flexible product, fewer part types in inventory, and more efficient use of board space.

Compatibility with existing op amp pinouts provides flexibility to upgrade low gain amplifiers, while decreasing component count. Unlike most buffers, the standard pinout provides an upgrade path should a higher closed loop gain be needed at a future date.

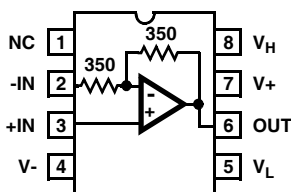
Detailed electrical specifications are contained in SMD 5962F9678501VPA, available on the Intersil Website.

A **Cross Reference Table** is available on the Intersil Website for conversion of Intersil Part Numbers to SMDs. The address is: www.intersil.com/military/crossref.asp

SMD numbers must be used to order Radiation Hardened Products.

Pinout

HS-1115RH
MIL-STD-1835, GDIP1-T8
(PDIP, Cerdip)
TOP VIEW



Application Information

Closed Loop Gain Selection

The HS-1115RH features a novel design which allows the user to select from three closed loop gains, without any external components. The result is a more flexible product, fewer part types in inventory, and more efficient use of board space.

This "buffer" operates in closed loop gains of -1, +1, or +2, and gain selection is accomplished via connections to the $\pm$ inputs. Applying the input signal to +IN and floating -IN selects a gain of +1 (see next section for layout caveats), while grounding -IN selects a gain of +2. A gain of -1 is obtained by applying the input signal to -IN with +IN grounded.

The table below summarizes these connections:

GAIN (A _{CL})	CONNECTIONS	
	+INPUT (PIN 3)	-INPUT (PIN 2)
-1	GND	Input
+1	Input	NC (Floating)
+2	Input	GND

Unity Gain Considerations

Unity gain selection is accomplished by floating the -Input of the HS-1115RH. Anything that tends to short the -Input to GND, such as stray capacitance at high frequencies, will cause the amplifier gain to increase toward a gain of +2. The result is excessive high frequency peaking, and possible instability. Even the minimal amount of capacitance associated with attaching the -Input lead to the PCB results in approximately 3dB of gain peaking. At a minimum this requires due care to ensure the minimum capacitance at the -Input connection.

Table 1 lists five alternate methods for configuring the HS-1115RH as a unity gain buffer, and the corresponding performance. The implementations vary in complexity and involve performance trade-offs. The easiest approach to implement is simply shorting the two input pins together, and applying the input signal to this common node. The amplifier bandwidth drops from 400MHz to 200MHz, but excellent gain flatness is the benefit. Another drawback to this approach is that the amplifier input noise voltage and input offset voltage terms see a gain of +2, resulting in higher noise and output offset voltages. Alternately, a 100pF capacitor between the inputs shorts them only at high frequencies, which prevents the increased output offset voltage but delivers less gain flatness.

Another straightforward approach is to add a 620 Ω resistor in series with the positive input. This resistor and the HS-1115RH input capacitance form a low pass filter which rolls off the signal bandwidth before gain peaking occurs. This configuration was employed to obtain the datasheet AC and transient parameters for a gain of +1.

PC Board Layout

The frequency response of this amplifier depends greatly on the amount of care taken in designing the PC board. **The use of low inductance components such as chip resistors and chip capacitors is strongly recommended, while a solid ground plane is a must!**

Attention should be given to decoupling the power supplies. A large value (10 μ F) tantalum in parallel with a small value (0.1 μ F) chip capacitor works well in most cases.

Terminated microstrip signal lines are recommended at the input and output of the device. Capacitance directly on the output must be minimized, or isolated as discussed in the next section.

For unity gain applications, care must also be taken to minimize the capacitance to ground seen by the amplifier's inverting input. At higher frequencies this capacitance will tend to short the -INPUT to GND, resulting in a closed loop gain which increases with frequency. This will cause excessive high frequency peaking and potentially other problems as well.

An example of a good high frequency layout is the Evaluation Board shown in Figure 1.

Driving Capacitive Loads

Capacitive loads, such as an A/D input, or an improperly terminated transmission line will degrade the amplifier's phase margin resulting in frequency response peaking and possible oscillations. In most cases, the oscillation can be avoided by placing a resistor (R_S) in series with the output prior to the capacitance.

R_S and C_L form a low pass network at the output, thus limiting system bandwidth well below the amplifier bandwidth of 225MHz. By decreasing R_S as C_L increases the maximum bandwidth is obtained without sacrificing stability.

TABLE 1. UNITY GAIN PERFORMANCE FOR VARIOUS IMPLEMENTATIONS

APPROACH	PEAKING (dB)	BW (MHz)	+SR/-SR (V/ μ s)	± 0.1 dB GAIN FLATNESS (MHz)
Remove Pin 2	2.5	400	1200/850	20
+ $R_S = 620\Omega$	0.6	170	1125/800	25
+ $R_S = 620\Omega$ and Remove Pin 2	0	165	1050/775	65
Short Pins 2, 3	0	200	875/550	45
100pF cap. between pins 2, 3	0.2	190	900/550	19

Evaluation Board

The performance of the HS-1115RH may be evaluated using the HFA11XX Evaluation Board, slightly modified as follows:

1. Remove the 500Ω feedback resistor (R2), and leave the connection open.
2. a. For $A_V = +1$ evaluation, remove the 500Ω gain setting resistor (R1), and leave pin 2 floating.
b. For $A_V = +2$, replace the 500Ω gain setting resistor with a 0Ω resistor to GND.

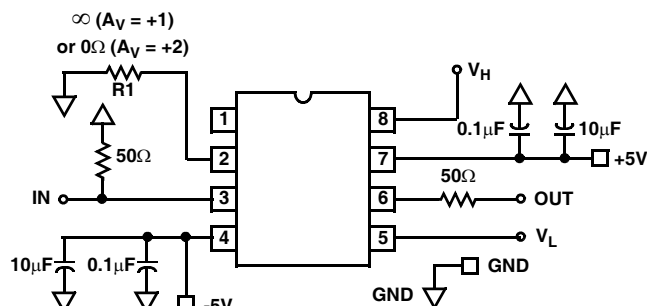


FIGURE 1A. SCHEMATIC

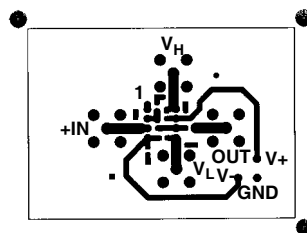


FIGURE 1B. TOP LAYOUT

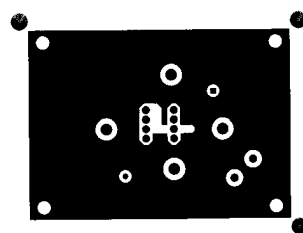
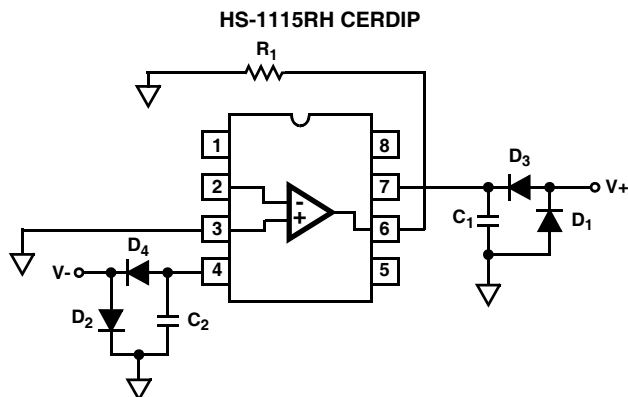


FIGURE 1C. BOTTOM LAYOUT

FIGURE 1. EVALUATION BOARD SCHEMATIC AND LAYOUT

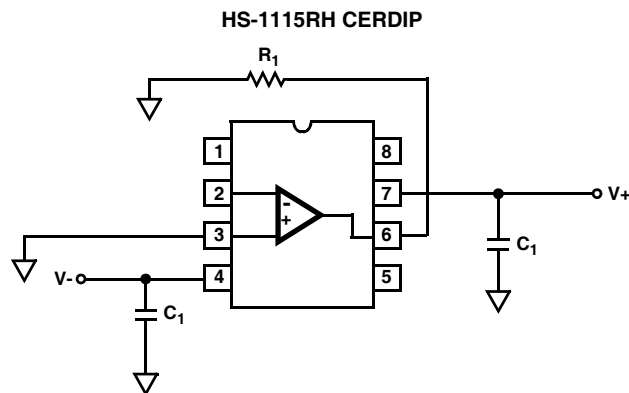
Burn-In Circuit



NOTES:

$R_1 = 100\Omega, \pm 5\%$ (Per Socket)
 $C_1 = C_2 = 0.01\mu F$ (Per Socket) or $0.1\mu F$ (Per Row) Minimum
 $D_1 = D_2 = 1N4002$ or Equivalent (Per Board)
 $D_3 = D_4 = 1N4002$ or Equivalent (Per Socket)
 $V_+ = +5.5V \pm 0.5V$
 $V_- = -5.5V \pm 0.5V$

Irradiation Circuit



NOTES:

$R_1 = 100\Omega, \pm 5\%$
 $C_1 = 0.01\mu F$
 $V_+ = +5.0V \pm 0.5V$
 $V_- = -5.0V \pm 0.5V$

Die Characteristics

DIE DIMENSIONS:

59 mils x 58.2 mils x 19 mils ± 1 mil
1500 μ m x 1480 μ m x 483 μ m $\pm 25.4\mu$ m

METALLIZATION:

Type: Metal 1: AlCu(2%)/TiW
Thickness: Metal 1: 8k $\text{\AA}$ $\pm 0.4\text{k}\text{\AA}$
Type: Metal 2: AlCu(2%)
Thickness: Metal 2: 16k $\text{\AA}$ $\pm 0.8\text{k}\text{\AA}$

GLASSIVATION:

Type: Nitride
Thickness: 4k $\text{\AA}$ $\pm 0.5\text{k}\text{\AA}$

WORST CASE CURRENT DENSITY:

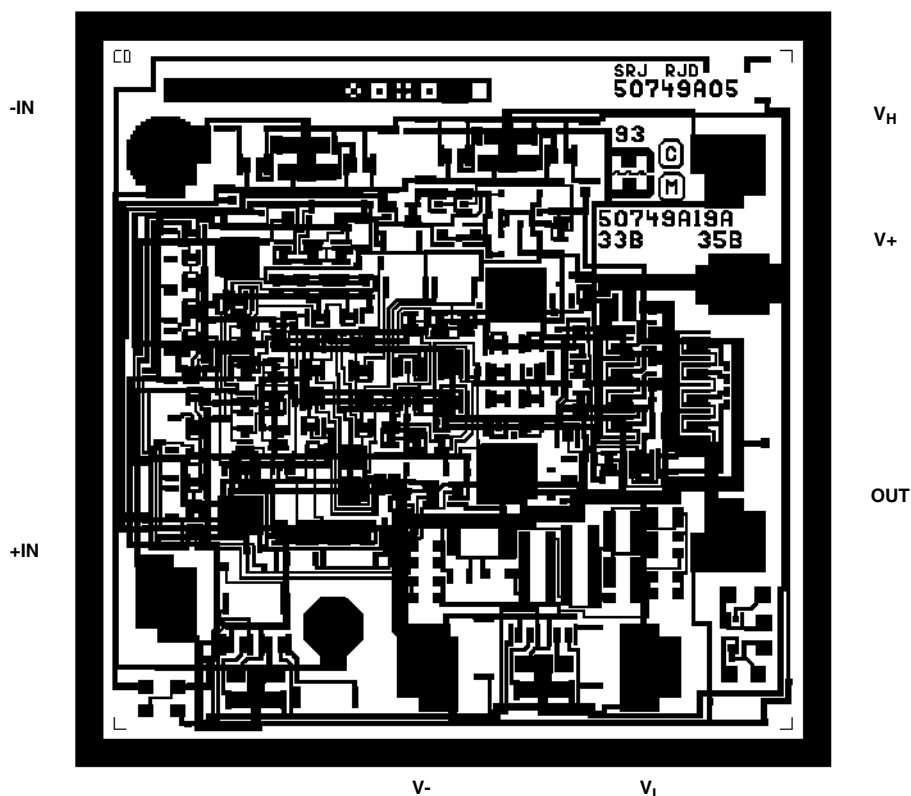
$< 2 \times 10^5 \text{ A/cm}^2$

TRANSISTOR COUNT: 89

SUBSTRATE POTENTIAL (Powered Up): Floating

Metallization Mask Layout

HS-1115RH



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